

<b>Notice of References Cited</b>		Application/Control No.	Applicant(s)/Patent Under Reexamination	
		10/721,323	YUN ET AL.	
Examiner		Art Unit		Page 1 of 1
Shean C Wu		1756		

**U.S. PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
	A	US-4,970,022	11-1990	Scheuble et al.	252/299.61
	B	US-6,716,491	04-2004	Tarumi et al.	428/1.1
	C	US-2002/0030180	03-2002	Tarumi et al.	252/299.61
	D	US-			
	E	US-			
	F	US-			
	G	US-			
	H	US-			
	I	US-			
	J	US-			
	K	US-			
	L	US-			
	M	US-			

**FOREIGN PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N	DE-10133867	04-2002	German	---	---
	O	JP 2002/12871	01-2002	Japan	---	---
	P					
	Q					
	R					
	S					
	T					

**NON-PATENT DOCUMENTS**

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	English translation by computer for JP 2002-12871, <a href="http://www4.ipdl.jpo.go.jp/Tokujitu/PAJdetail.ipdl?N0000=60&amp;N0120=01&amp;N2001=2&amp;N3001=2002-012871">http://www4.ipdl.jpo.go.jp/Tokujitu/PAJdetail.ipdl?N0000=60&amp;N0120=01&amp;N2001=2&amp;N3001=2002-012871</a>
	V	
	W	
	X	

\*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)  
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